


<b>Search Notes</b>  	<b>Application/Control No.</b>  10572725	<b>Applicant(s)/Patent Under Reexamination</b>  HAN ET AL.
	<b>Examiner</b>  Hsieh, Ping Y	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	76, 85, 86, 87, 118, 147, 148, 165.1, 183.1, 323, 324	11/12/08	PH

SEARCH NOTES		
Search Notes	Date	Examiner
Text search in EAST (see search history)	11/12/08	PH
PLUS search	1/28/08	PH
Consulted with Yuwen Pan, Wen Huang	11/12/08	PH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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Examiner.Art Unit 2618